

Form PTO-1449 COMMERCE (REV. 7-80)		U.S. DEPARTMENT OF PATENT AND TRADEMARK OFFICE		DOCKET NO. NL 000770		Serial No. 09/940819 no 8/17/84										
				Applicant Rene Monshouwer et al		Group 2877 no 8/17/84										
				Filing Date Concurrently												
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)																
U.S. PATENT DOCUMENTS																
Ex. Int.		Document Number								Date	Name	Class	Sub-class	Filing Date If Approp.		
no	AA	5	1	4	4	3	6	3	9/1/92	Wittekoek et al	355	53	1/24/91			
no	AB	4	5	4	0	2	7	7	9/10/85	Mayer et al	355	53	6/24/83			
no	AC	4	7	3	7	8	2	3	4/12/88	Bouwer et al	355	53	10/14/86			
no	AD	5	0	2	6	1	6	6	6/25/91	Van der Werf	356	401	10/1/84			
no	AE	5	1	9	1	2	0	0	3/2/93	Van der Werf	250	201	12/16/91			
no	AF	4	3	5	6	3	9	2	10/26/82	Wittekoek et al	250	201	6/11/80			
no	AG	4	8	6	1	1	6	2	8/29/89	Ina et al	356	401	11/15/88			
no	AH	5	4	1	4	5	1	4	5/9/95	Smith et al	356	363	6/1/93			
no	AI	4	7	7	8	2	7	5	10/18/88	Van den Brink	356	401	9/24/86			
no	AJ	4	2	5	1	1	6	0	2/17/81	Bouwuis et al	356	401	7/13/78			
no	AK	5	2	4	3	1	9	5	9/7/93	Nishi	250	548	12/29/92			
FOREIGN PATENT DOCUMENTS																
		Document Number								Date	Country	Class	Sub-Class	Trans.		
														Yes	No	
no	AL	0	4	9	8	4	9	9	A	1	8/12/92	Europe			X	
no	AM	9	8	3	9	6	8	9	A	1	9/11/98	World			X	
OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)																
no	AN	"Submicrometer Lithographic Alignment and Overlay Strategies", by Saleem H. Zaidi et al, SPIE Vol. 1343, 1990, pages 245-255.														
no	AO	"Submicron 1:1 Optical Lighography", by David A. Markle, Semiconductor International May 1986.														
Examiner <i>Gregory</i>											Date Considered 8/17/84					

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